

Notice of References Cited

Application/Control No.

10/523,994

Applicant(s)/Patent Under
Reexamination
TANAKA ET AL.

Examiner

HOANG TRAN

Art Unit

2874

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0109650	06-2004	Kim et al.	385/100
*	B	US-2003/0158309	08-2003	Ono et al.	524/261
*	C	US-2003/0128938	07-2003	Caveney, Jack E.	385/81
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NON-PATENT DOCUMENTS

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